TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

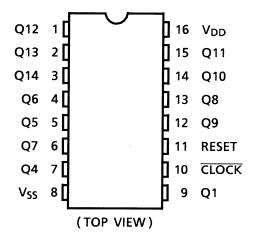
# TC4020BP,TC4020BF,TC4020BFN

### TC4020B 14 Stage Ripple-Carry Binary Counter/Dividers

TC4020B is 14 stage ripple carry binary counter having asynchronous clear function. The counter advances its counting stage by falling edge of  $\overline{CLOCK}$  input. When  $RE\underline{SET}$  input is placed "H", all the circuits are reset regardless of  $\overline{CLOCK}$  input making all the outputs (Q1, Q4~Q14) to be "L".

This is most suitable for frequency dividers, control circuits and timing circuits.

#### **Pin Assignment**



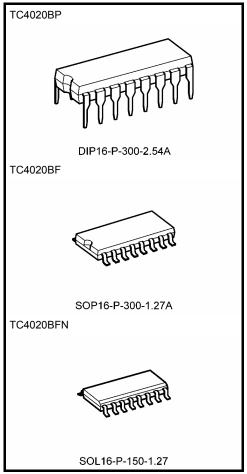
#### **Truth Table**

$\overline{CLOCK}\ \Delta$	RESET	Output State
*	Н	All Outputs = "L"
	L	No Change
$\neg$	L	Advance to Next State

Δ: Level change

\*: Don't care

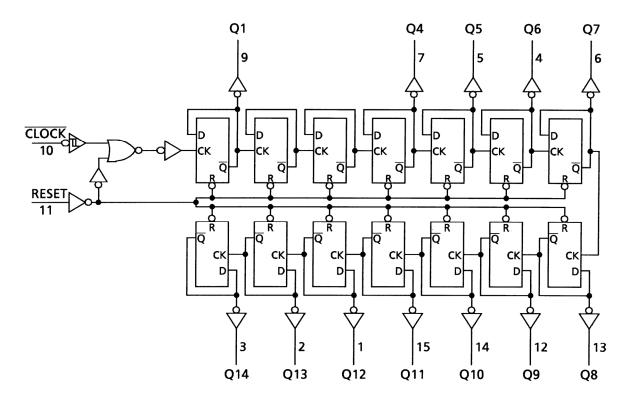
Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.)

### **Logic Diagram**



### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	V <sub>SS</sub> - 0.5~V <sub>SS</sub> + 20	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> – 0.5~V <sub>DD</sub> + 0.5	٧
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> – 0.5~V <sub>DD</sub> + 0.5	٧
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T <sub>opr</sub>	-40~85	°C
Storage temperature range	T <sub>stg</sub>	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Operating Ranges (V<sub>SS</sub> = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>	_	0	_	V <sub>DD</sub>	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

2 2007-10-01



# Static Electrical Characteristics ( $V_{SS} = 0 V$ )

		Sym-	Test Condition		-40°C		25°C			85°C		
Charac	teristics	bol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
			11	5	4.95		4.95	5.00	_	4.95		
High-level voltage	output	V <sub>OH</sub>	$ I_{OUT}  < 1 \mu A$ $V_{IN} = V_{SS}, V_{DD}$	10	9.95	_	9.95	10.00	_	9.95	_	V
J			VIN - VSS, VDD	15	14.95		14.95	15.00	_	14.95	_	
			  I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05	
Low-level voltage	output	$V_{OL}$	$V_{IN} = V_{SS}, V_{DD}$	10	_	0.05	_	0.00	0.05	_	0.05	V
			VIIV - VSS, VDD	15	_	0.05	_	0.00	0.05	_	0.05	
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_	
			V <sub>OH</sub> = 2.5 V	5	-2.50	_	-2.10	-4.0	_	-1.70	_	mA
Output hig	h current	loh	V <sub>OH</sub> = 9.5 V	10	-1.50	_	-1.30	-2.2	_	-1.10	_	
			V <sub>OH</sub> = 13.5 V	15	-4.00	_	-3.40	-9.0	_	-2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		la.	V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.2	_	0.42	_	mA
Output low	v current		V <sub>OL</sub> = 0.5 V	10	1.50	_	1.30	3.2	_	1.10	_	
Output low current	l <sub>OL</sub>	V <sub>OL</sub> = 1.5 V	15	4.00	_	3.40	12.0	_	2.80	_	111/	
		$V_{IN} = V_{SS}, V_{DD}$										
		V <sub>IH</sub>	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	3.5		3.5	2.75	_	3.5	_	V
Input high	voltago		V <sub>OUT</sub> = 1.0 V, 9.0 V	10	7.0	_	7.0	5.50	_	7.0	_	
input nign	voitage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	_	11.0	8.25	_	11.0	_	
			$ I_{OUT}  < 1 \mu A$									
			V <sub>OUT</sub> = 0.5 V, 4.5 V	5		1.5	_	2.25	1.5	_	1.5	
Input low voltage		V <sub>IL</sub>	V <sub>OUT</sub> = 1.0 V, 9.0 V	10	_	3.0	_	4.50	3.0	_	3.0	٧
			V <sub>OUT</sub> = 1.5 V, 13.5 V	15	_	4.0	_	6.75	4.0	_	4.0	
			$ I_{OUT}  < 1 \mu A$									
Input	"H" level	I <sub>IH</sub>	V <sub>IH</sub> = 18 V	18	_	0.1	_	10 <sup>-5</sup>	0.1	_	1.0	μА
current	"L" level	I <sub>IL</sub>	V <sub>IL</sub> = 0 V	18	_	-0.1	_	-10 <sup>-5</sup>	-0.1	_	-1.0	μΑ
			V V V	5	_	5	_	0.005	5	_	150	
Quiescent current	Quiescent supply current		$V_{IN} = V_{SS}, V_{DD}$	10	_	10	_	0.010	10	_	300	μΑ
			(Note)	15	_	20	—	0.015	20	_	600	

3

Note: All valid input combinations.



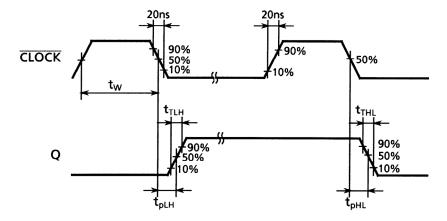
# Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}$ = 0 V, $C_L$ = 50 pF)

Observantanistiss	O was bas I	Test Condition	N.A.	T	May	l lmit	
Characteristics	Symbol		V <sub>DD</sub> (V)	Min	Тур.	Max	Unit
Output transition time			5	_	70	200	
	t <sub>TLH</sub>	_	10	_	35	100	ns
(low to high)			15	_	30	80	
Output transition time			5	_	70	200	
Output transition time	t <sub>THL</sub>	_	10	_	35	100	ns
(high to low)			15	_	30	80	
Decreasion delevitimes			5	_	160	360	
Propagation delay time	t <sub>pLH</sub>	_	10	_	80	160	ns
(CLOCK -Q1)			15	_	65	130	
			5	_	160	360	
Propagation delay time	t <sub>pHL</sub>	_	10	_	80	160	ns
(CLOCK -Q1)			15	_	65	130	
Decrease firm delevitimes			5	_	1000	2000	
Propagation delay time	t <sub>pLH</sub>	_	10	_	500	1000	ns
(CLOCK -Q14)	·		15	_	400	800	
Decrease firm delevitimes			5	_	1000	2000	
Propagation delay time	t <sub>pHL</sub>	_	10	_	500	1000	ns
(CLOCK -Q14)			15	_	400	800	
B			5	_	150	280	
Propagation delay time	t <sub>pHL</sub>	_	10	_	70	120	ns
(RESET-Q)			15	_	50	100	
			5	3.5	10	_	
Max clock frequency	f <sub>CL</sub>	_	10	8.0	20	_	MHz
			15	12.0	25	_	
			5	_	50	140	
Min clock pulse width	t <sub>W</sub>	_	10	_	20	60	ns
(RESET)			15	_	15	40	
			5	_	100	200	
Min pulse width	t <sub>W</sub>	_	10	_	40	80	ns
			15	_	30	60	
			5	_	_	350	
Min removal time	t <sub>rem</sub>	_	10	_	_	150	ns
(RESET- CLOCK )			15	_	_	100	
			5				
Max clock input rise time	t <sub>rCL</sub>	_	10	No limit			μS
Max clock input fall time	t <sub>fCL</sub>		15				
Input capacitance	C <sub>IN</sub>	_	ı	_	5	7.5	pF

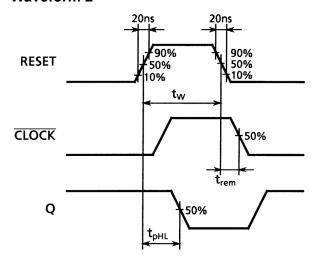
4

# **Operating Supply Current Test Circuit**

### Waveform 1



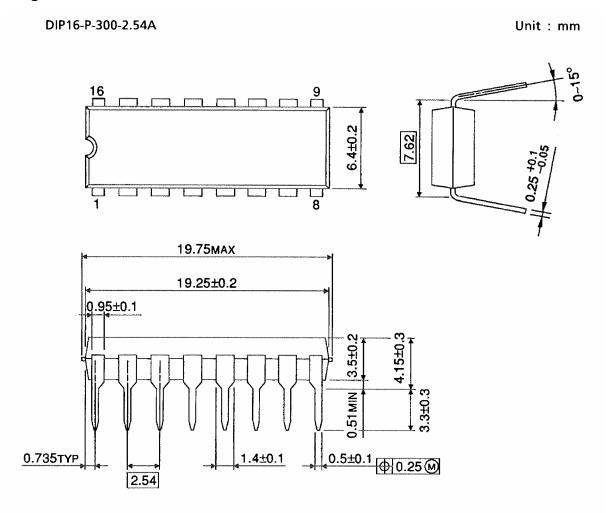
### Waveform 2



5



# **Package Dimensions**

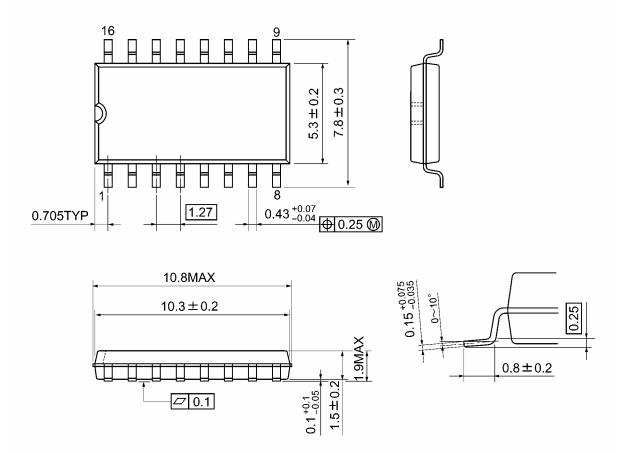


6

Weight: 1.00 g (typ.)

# **Package Dimensions**

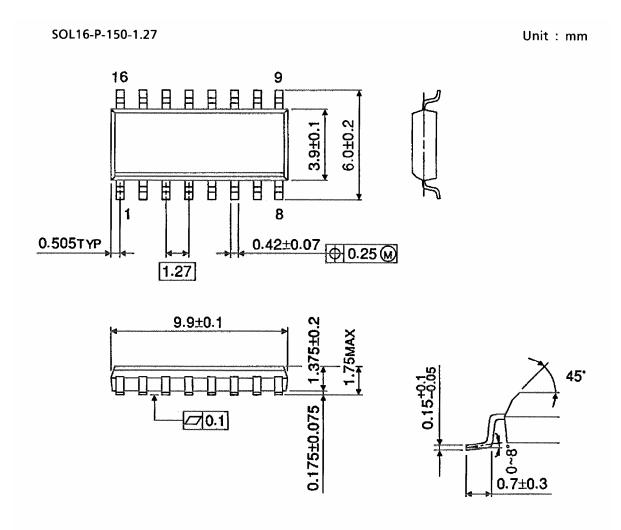
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)



# **Package Dimensions (Note)**



8

Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS
  compatibility. Please use these products in this document in compliance with all applicable laws and regulations
  that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses
  occurring as a result of noncompliance with applicable laws and regulations.

9